



Support & training



CSD17381F4

SLPS411G - APRIL 2013 - REVISED JANUARY 2022

# CSD17381F4 30-V N-Channel FemtoFET<sup>™</sup> MOSFET

## 1 Features

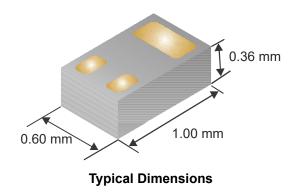
- Ultra-low on-resistance
- Ultra-low Q<sub>g</sub> and Q<sub>gd</sub>
- Low threshold voltage
- Ultra-small footprint (0402 case size)
  1.0 mm × 0.6 mm
  - Ultra-low profile
  - 0.36 mm height
- Integrated ESD protection diode
  - Rated >4 kV HBM
  - Rated >2 kV CDM
- Lead and halogen free
- RoHS compliant

## **2** Applications

- Optimized for load switch applications
- Optimized for general purpose switching applications
- · Single-cell battery applications
- · Handheld and mobile applications

## **3 Description**

This 90 m $\Omega$ , 30 V N-Channel FemtoFET<sup>M</sup> MOSFET technology is designed and optimized to minimize the footprint in many handheld and mobile applications. This technology is capable of replacing standard small signal MOSFETs while providing at least a 60% reduction in footprint size.



#### **Product Summary**

T <sub>A</sub> = 25°	°C	TYPICAL V	UNIT	
V <sub>DS</sub>	Drain-to-source voltage	30		V
Qg	Gate charge total (4.5 V)	1040		рС
Q <sub>gd</sub>	Gate charge gate-to-drain	133		рС
		V <sub>GS</sub> = 1.8 V	160	mΩ
R <sub>DS(on)</sub>	Drain-to-source on-resistance	V <sub>GS</sub> = 2.5 V 110		mΩ
		V <sub>GS</sub> = 4.5 V 90		mΩ
V <sub>GS(th)</sub>	Threshold voltage	0.85		V

#### **Ordering Information**

DEVICE <sup>(1)</sup>	QTY	MEDIA	PACKAGE	SHIP							
CSD17381F4	3000	7-Inch	Femto (0402) 1.0 mm	Tape and							
CSD17381F4T	250	reel	×0.6 mm SMD Lead Less	reel							

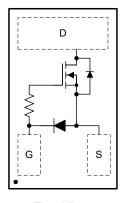
(1) For all available packages, see the orderable addendum at the end of the data sheet.

T <sub>A</sub> = 25	°C unless otherwise stated	VALUE	UNIT								
V <sub>DS</sub>	Drain-to-source voltage	30	V								
V <sub>GS</sub>	Gate-to-source voltage	12	V								
I <sub>D</sub>	Continuous drain current, $T_A = 25^{\circ}C^{(1)}$	3.1	A								
I <sub>DM</sub>	Pulsed Drain Current, $T_A = 25^{\circ}C^{(2)}$	12	A								
1.	Continuous gate clamp current	35	mA								
I <sub>G</sub>	Pulsed gate clamp current <sup>(2)</sup>	350									
PD	Power dissipation <sup>(1)</sup>	500	mW								
ESD	Human body model (HBM)	4	kV								
Rating	Charged device model (CDM)	2	kV								
T <sub>J</sub> , T <sub>stg</sub>	Operating junction and storage temperature range	-55 to 150	°C								
E <sub>AS</sub>	Avalanche energy, single pulse I <sub>D</sub> = 7.4 A, L = 0.1 mH, R <sub>G</sub> = 25 $\Omega$	2.7	mJ								

#### Absolute Maximum Ratings

(1) Typical  $R_{0JA}$  = 90°C/W on 1 inch<sup>2</sup> (6.45 cm<sup>2</sup>), 2 oz. (0.071 mm thick) Cu pad on a 0.06 inch (1.52 mm) thick FR4 PCB.

(2) Pulse duration  $\leq 100 \ \mu$ s, duty cycle  $\leq 1\%$ .



**Top View** 



## **Table of Contents**

1 Features1	
2 Applications1	
3 Description	
4 Revision History	
5 Specifications	
5.1 Electrical Characteristics	
5.2 Thermal Information	
5.3 Typical MOSFET Characteristics4	
6 Device and Documentation Support	

	6.1 Support Resources	7
	6.2 Trademarks	
	6.3 Electrostatic Discharge Caution	7
	6.4 Glossary	7
7	Mechanical, Packaging, and Orderable Information	
	7.1 Mechanical Dimensions	8
	7.2 Recommended Minimum PCB Layout	9
	7.3 Recommended Stencil Pattern	. 9

## **4 Revision History**

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

C	hanges from Revision F (October 2021) to Revision G (January 2022)	Page
•	Changed height dimension from "0.35 mm" to "0.36 mm" Features	1
•	Changed height dimension from "0.35 mm" to "0.36 mm" in Typical Dimensions	1
•	Changed height dimension from "0.35 mm" to "0.36 mm" in Mechanical Dimensions	<mark>8</mark>

C	hanges from Revision E (December 2017) to Revision F (October 2021)	Page
•	Updated the numbering format for tables, figures, and cross-references throughout the document	1
•	Changed footnote to refer to correct support document	9

Cł	hanges from Revision D (August 2014) to Revision E (December 2017)	Page
•	Changed Pulsed Drain Current value From: 10 A To: 12 A in the Absolute Maximum Ratings table	1
•	Change Note 2 From: Pulse duration ≤300 µs, duty cycle ≤2% To: Pulse duration ≤ 100 µs, duty cycle ≤	1%. <mark>1</mark>
•	Updated Figure 5-1.	4
	Updated Figure 5-10 with newly measured data.	
•	Updated all mechanical drawings, increased the size of the pads in Section 7.3	<mark>8</mark>



## **5** Specifications

## **5.1 Electrical Characteristics**

(T<sub>A</sub> = 25°C unless otherwise stated)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
STATIC	CHARACTERISTICS	I				
BV <sub>DSS</sub>	Drain-to-Source Voltage	V <sub>GS</sub> = 0 V, I <sub>DS</sub> = 250 μA	30			V
I <sub>DSS</sub>	Drain-to-Source Leakage Current	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 24 V			100	nA
I <sub>GSS</sub>	Gate-to-Source Leakage Current	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = 10 V			50	nA
V <sub>GS(th)</sub>	Gate-to-Source Threshold Voltage	$V_{DS}$ = $V_{GS}$ , $I_{DS}$ = 250 $\mu$ A	0.65	0.85	1.10	V
		V <sub>GS</sub> = 1.8 V, I <sub>DS</sub> =0.5 A		160	250	mΩ
п	Drain-to-Source On-Resistance	V <sub>GS</sub> = 2.5 V, I <sub>DS</sub> =0.5 A		110	143	mΩ
R <sub>DS(on)</sub>	Dram-to-Source On-Resistance	V <sub>GS</sub> = 4.5 V, I <sub>DS</sub> = 0.5 A		90	117	mΩ
		V <sub>GS</sub> = 8 V, I <sub>DS</sub> =0.5 A		84	109	mΩ
9 <sub>fs</sub>	Transconductance	V <sub>DS</sub> = 15 V, I <sub>DS</sub> = 0.5 A		4.8		S
DYNAMI	C CHARACTERISTICS	I			I	
C <sub>iss</sub>	Input Capacitance			150	195	pF
C <sub>oss</sub>	Output Capacitance	$V_{GS} = 0 V, V_{DS} = 15 V,$ f = 1 MHz		44	57	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	J		2.2	2.9	pF
R <sub>G</sub>	Series Gate Resistance			23		Ω
Q <sub>g</sub>	Gate Charge Total (4.5 V)			1040	1350	рС
Q <sub>gd</sub>	Gate Charge Gate-to-Drain			133		pC
Q <sub>gs</sub>	Gate Charge Gate-to-Source			226		pC
Q <sub>g(th)</sub>	Gate Charge at V <sub>th</sub>			150		pC
Q <sub>oss</sub>	Output Charge	V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 0 V		1110		рС
t <sub>d(on)</sub>	Turn On Delay Time			3.4		ns
t <sub>r</sub>	Rise Time	V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 4.5 V,		1.4		ns
t <sub>d(off)</sub>	Turn Off Delay Time	$I_{DS} = 0.5 \text{ A}, \text{R}_{\text{G}} = 2 \Omega$		10.8		ns
t <sub>f</sub>	Fall Time			3.6		ns
DIODE C	CHARACTERISTICS	· · · · · · · · · · · · · · · · · · ·			I	
V <sub>SD</sub>	Diode Forward Voltage	I <sub>SD</sub> = 0.5 A, V <sub>GS</sub> = 0 V		0.73	0.9	V
Q <sub>rr</sub>	Reverse Recovery Charge	$V_{1} = 4EV_{1} = 0EA di/dt = 200 A/max$		1500		рС
t <sub>rr</sub>	Reverse Recovery Time	V <sub>DS</sub> = 15 V, I <sub>F</sub> = 0.5 A, di/dt = 300 A/μs		5.6		ns

## **5.2 Thermal Information**

 $(T_A = 25^{\circ}C \text{ unless otherwise stated})$ 

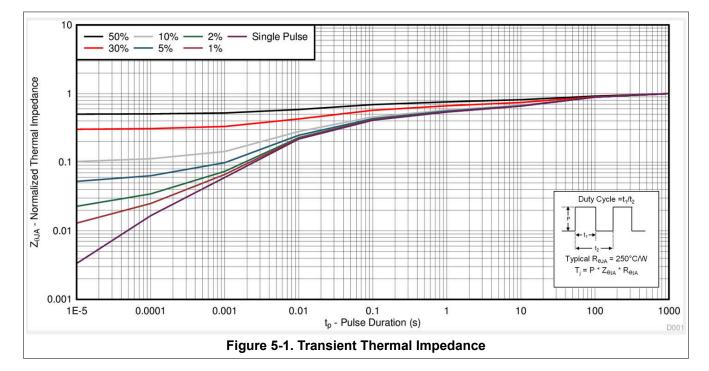
	THERMAL METRIC	TYPICAL VALUES	UNIT
	Junction-to-Ambient Thermal Resistance <sup>(1)</sup>	90	°C/W
R <sub>θJ</sub>	Junction-to-Ambient Thermal Resistance <sup>(2)</sup>	250	0/10

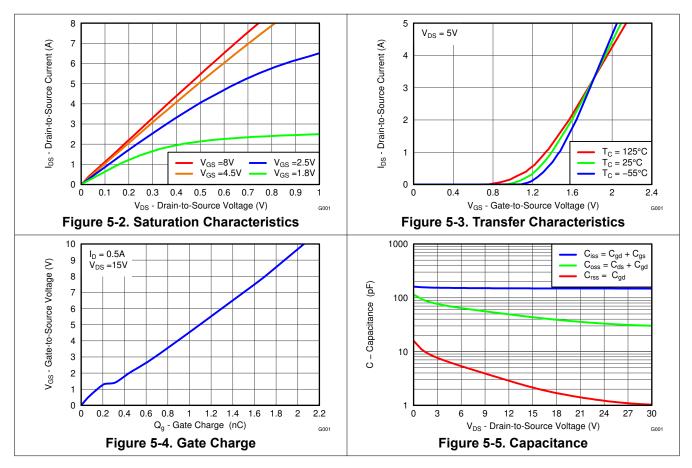
Device mounted on FR4 material with 1 inch<sup>2</sup> (6.45 cm<sup>2</sup>), 2 oz. (0.071 mm thick) Cu.
 Device mounted on FR4 material with minimum Cu mounting area.



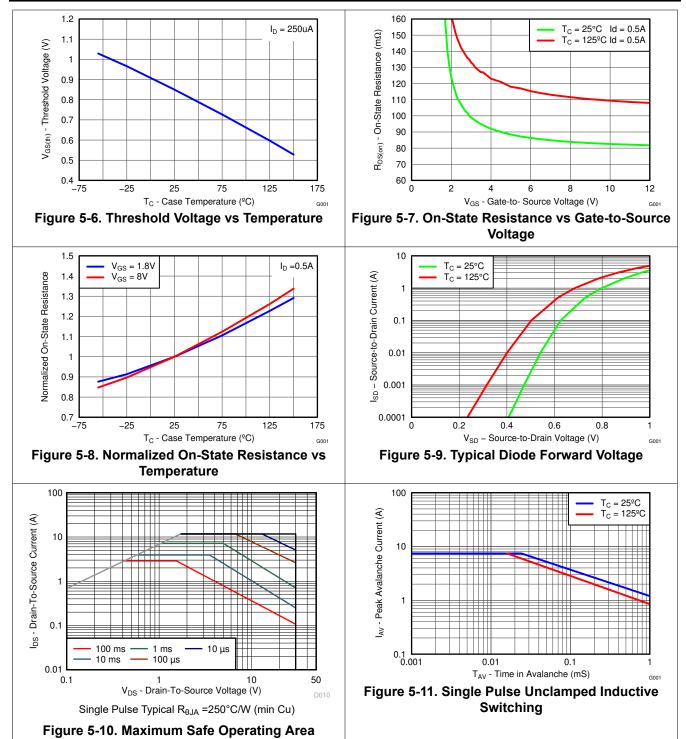
## **5.3 Typical MOSFET Characteristics**

 $(T_A = 25^{\circ}C \text{ unless otherwise stated})$ 

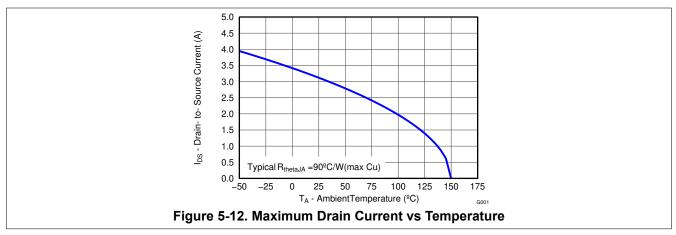














## 6 Device and Documentation Support

### 6.1 Support Resources

TI E2E<sup>™</sup> support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

#### 6.2 Trademarks

FemtoFET<sup>™</sup> are trademarks of Texas Instruments.

TI E2E<sup>™</sup> is a trademark of Texas Instruments.

All trademarks are the property of their respective owners.

#### 6.3 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

#### 6.4 Glossary

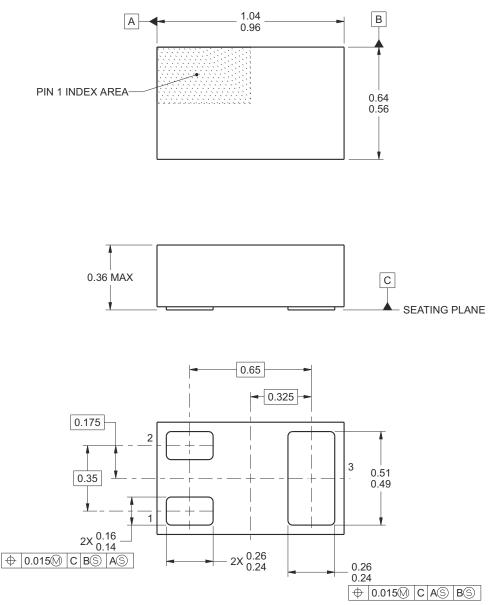
TI Glossary This glossary lists and explains terms, acronyms, and definitions.



## 7 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

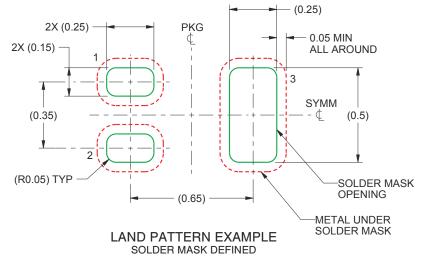
#### 7.1 Mechanical Dimensions



- A. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- B. This drawing is subject to change without notice.
- C. This package is a Pb-free bump design. Bump finish may vary. To determine the exact finish, refer to the device data sheet or contact a local TI representative.



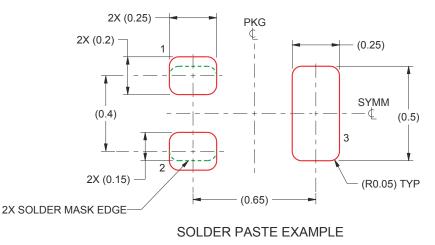
### 7.2 Recommended Minimum PCB Layout



A. All dimensions are in millimeters.

B. For more information, see FemtoFET Surface Mount Guide (SLRA003D).

#### 7.3 Recommended Stencil Pattern



- A. All dimensions are in millimeters.
- B. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



### PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
CSD17381F4	ACTIVE	PICOSTAR	YJC	3	3000	RoHS & Green	NIAU	Level-1-260C-UNLIM	-55 to 150	CQ	Samples
CSD17381F4T	ACTIVE	PICOSTAR	YJC	3	250	RoHS & Green	NIAU	Level-1-260C-UNLIM	-55 to 150	CQ	Samples

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

<sup>(2)</sup> RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

**RoHS Exempt:** TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

<sup>(3)</sup> MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

<sup>(4)</sup> There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

<sup>(5)</sup> Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

<sup>(6)</sup> Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

**Important Information and Disclaimer:**The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.



www.ti.com

## PACKAGE OPTION ADDENDUM

11-Jan-2022



Texas

STRUMENTS

## TAPE AND REEL INFORMATION





#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All	dimensions are nominal												
	Device	-	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
	CSD17381F4	PICOSTAF	YJC	3	3000	180.0	8.4	0.7	1.1	0.46	4.0	8.0	Q2
	CSD17381F4T	PICOSTAF	YJC	3	250	180.0	8.4	0.7	1.1	0.46	4.0	8.0	Q2



www.ti.com

# PACKAGE MATERIALS INFORMATION

8-Jun-2024



\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CSD17381F4	PICOSTAR	YJC	3	3000	182.0	182.0	20.0
CSD17381F4T	PICOSTAR	YJC	3	250	182.0	182.0	20.0

## IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATA SHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products.

TI objects to and rejects any additional or different terms you may have proposed.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2024, Texas Instruments Incorporated